Session 6C — IP Session: Test Strategies of Leading Edge SoCs

Organizer: Kazumi Hatayama, Renesas Technology Corp.

In this session, various case studies of leading edge SoCs testing are presented with advanced ideas for effective and efficient testing.

Presentations:

The Application and Enhancement of Test Cost Reduction Method for SoCs
Tatsuru Matsuo (speaker), Takahisa Hiraide, Fujitsu Laboratories Ltd.
Hideaki Konishi, Michiaki Emori, Takashi Aikyo, Fujitsu Ltd.
Masayuki Arai, Satoshi Fukumoto, Kazuhiko Iwasaki, Tokyo Metropolitan University

Failure and Critical-Path Analysis Using Logic BIST
Naoki Kiryu (speaker), Toshiba Corp.

Strategies for Reducing Test Cost of SoCs
Michinobu Nakao (speaker), Hiroki Wada, Kazumi Hatayama, Hiroyuki Adachi, Renesas Technology Corp.